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# Trends and Prospects in Machine Learning Technologies: Deep Learning, Reinforcement Learning and Q-learning

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# **Message from the Guest Editors**

This Special Issue aims to publish original research of the highest scientific quality related to the trends and prospects in Deep Learning, Reinforcement Learning, and Q-Learning, the latest research trends in machine learning technology. We invite original and unpublished submissions that feature innovative methods enhancing modeling, learning and testing, data set creation and processing, and utilization of Deep Learning, Reinforcement Learning, and Q-Learning.

The scope includes theoretical and experimental studies that contribute to novel developments in fundamental research and its applications.











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## **Message from the Editor-in-Chief**

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